

**Appendix A**  
**NTETC Measuring Sector (MS)**  
**Action List – October 2009**

	<b>Responsible Party</b>	<b>Task</b>	<b>Details</b>	<b>Deadline</b>
1	Mike Keilty working with interested Sector members	Refine the example for a “separated technology” proposal and circulate it for review.	<ul style="list-style-type: none"> <li>▶Integrate the separated technology proposal with that presented at the 2009 Sector meeting.</li> <li>▶Circulate the newly edited version among Measuring Sector members.</li> </ul>	December 15, 2009, to complete a revised example of Policy C.
		Discuss revisions with interested Sector members.	<ul style="list-style-type: none"> <li>▶Discuss revision with members who are able to attend the January 2010 NCWM Interim Meeting.</li> <li>▶Solicit additional comments via electronic communication</li> </ul>	January 2010 Interim Meeting
		Make additional revisions and present draft to the Sector for review and approval.	<ul style="list-style-type: none"> <li>▶Make any additional revisions as needed.</li> <li>▶Distribute revised version to Sector.</li> </ul>	2010 Sector Meeting
3	Metrologically Significant Characteristics of Technologies Work Group (WG)  Chair: Rodney Cooper  Co-Chair: Rich Miller  Work Group: Marc Buttler Paul Glowacki Mike Guidry Gordon Johnson Dmitri Karimov Henry Oppermann Steve Patoray Dan Reiswig	Form new MS Metrologically Significant Characteristics of Technologies Work Group to arrive at a uniform, appropriate, and clear approach for initial, subsequent, and additional tests for the performance of a device technology	<ul style="list-style-type: none"> <li>▶Create a Short List features/options affecting the metrological characteristics of each device technology</li> <li>▶Provide a 1-page analysis that briefly documents and provides the rationale for including each metrological characteristic in the list</li> <li>▶WG reviews First Draft List of significant constituents and condenses to only relevant characteristics<sup>1</sup></li> <li>▶WG prepares Final List for its January 2010 NCWM Meeting<sup>2</sup></li> </ul>	<sup>1</sup> December 15, 2009, to complete the First Draft List that is ready for the WG's Review  <sup>2</sup> January 15, 2010, for the Final List for the WG's First Meeting
3	Mike Keilty Tina Butcher	Coordinate with NCWM to enable Metrologically Significant Characteristics of Technologies Work Group to meet briefly at the: (1) January 2010 NCWM Meeting and (2) July 2010 NCWM Meeting	<ul style="list-style-type: none"> <li>▶Contact NTEP Admin Director (Don Onwiler) for meeting approvals</li> </ul>	October 15, 2009

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2	Tina Butcher	Forward HydroCarbon (HC) Vapor Meter Checklist developed by CADMS for consideration of the NTEP CMTE	<ul style="list-style-type: none"> <li>▶Add HC Vapor Meter Checklist to NCWM Pub 14</li> <li>▶NOTE Input is needed on HC Vapor Meter Checklist from HC Vapor Meter OEMs</li> </ul>	November 1, 2009
4A	Test Criteria for an Electronic Indicator Submitted Separately from a Measuring Element for NTEP Evaluation Work Group: Rodney Cooper Maurice Forkert Dmitri Karimov Rich Miller Dave Rajala Ralph Richter	WG Provides Input on the Checklist developed by CADMS	<ul style="list-style-type: none"> <li>▶WG Provides Input to Dan Reiswig 1 month prior to March 2010 NTEP Lab Meeting</li> </ul>	February 2010
4B	Checklist Developer: Dan Reiswig	Modify the Checklist for Discussion at the March 2010 NTEP Lab Meeting	<ul style="list-style-type: none"> <li>▶Dan Reiswig Modifies Draft Checklist based on Input of the WG</li> </ul>	March 2010
4C	Checklist Developer: Dan Reiswig	MS Labs Discuss and Make Necessary Modification at the March 2010 NTEP Lab Meeting	<ul style="list-style-type: none"> <li>▶Dan Reiswig Modifies Draft Checklist based on Labs' Input from the March 2010 NTEP Lab Meeting</li> </ul>	Late August 2010 Final Draft Checklist Distributed 1 month prior to the Fall 2010 MS Meeting
4D	Dan Reiswig/Tina Butcher	Finalize the Checklist for the 2011 NCWM Pub 14	<ul style="list-style-type: none"> <li>▶Dan Reiswig works with Technical Advisor to incorporate input from Fall 2010 Sector meeting.</li> <li>▶If further Sector review is not required, Technical Advisor submits draft to the NTEP Committee to consider for 2011 Pub 14.</li> </ul>	November 1, 2010, MS Submits Final Checklist for consideration of the NTEP CMTE to include in the 2011 NCWM Pub 14
6A	Maurice Forkert Mike Frailer Mike Guidry Dmitri Karimov Rich Miller Lead: Steve Patoray Ken Smith	Clarify Policy G. Range of Data Points	<p>Bounce ideas off of Mike Frailer for:</p> <ul style="list-style-type: none"> <li>(1) Defining what is meant by multi-point calibration shall be <u>"blind and integral"</u> to the measuring element</li> <li>(2) Clarifying what is</li> </ul>	

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			meant by multi-point calibration shall be not " <u>accessible</u> " in the field	
6B	Maurice Forkert Mike Frailer Mike Guidry Dmitri Karimov Rich Miller Lead: Steve Patoray Ken Smith	Develop Language in Policy G. Range of Data Points to Allow for Uniform Interpretation and Application of the Criteria by the U.S. and Canadian Stakeholders	<ul style="list-style-type: none"> <li>▶In Policy G, where necessary to clarify the intent of the criteria:                             <ul style="list-style-type: none"> <li>(1) Modify Language</li> <li>(2) Define Terminology</li> </ul> </li> <li>▶Review and Discuss Modifications to Policy G. at the March 2010 Lab Mtg</li> </ul>	February 2010
9	Tina Butcher	Forward the MS Position on the Proposal to Modify HB44 General Code G-S.8 to the 2010 NCWM S&T CMTE	<ul style="list-style-type: none"> <li>▶Measuring Devices with CCs have been evaluated to either:                             <ul style="list-style-type: none"> <li>(1) not function in the calibration or configuration mode</li> <li>(2) not be sealed in the calibration or configuration mode or</li> <li>(3) clearly indicate the device is in the calibration or configuration mode</li> </ul> </li> <li>▶MS recommends no changes to paragraph G-S.8 since the intent is understood and appropriately applied by MS members</li> </ul>	November 1, 2009

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